

Description

The SI7139DP-T1-GE3 uses advanced trench technology to provide excellent R_{DS(ON)}, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = -30VI_{D} = -70A$

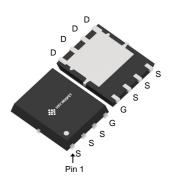
 $R_{DS(ON)}$ < $8.8 \text{m}\Omega$ V_{GS} =-10V

Application

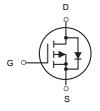
Battery protection

Load switch

Uninterruptible power supply



DFN5X6-8L (PowerPAK-SO-8)



P-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
SI7139DP-T1-GE3	DFN5X6-8L (PowerPAK-SO-8)	HXY MOSFET	5000

Absolute Maximum Ratings (Tc=25 ℃ unless otherwise noted)

Symbol	Parameter	Rating	Units
Vos	Drain-Source Voltage	-30	V
Vgs	Gate-Source Voltage	±20	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	-70	А
I _D @T _C =75°C	Continuous Drain Current, V _{GS} @ 10V ¹	-40	Α
Ірм	Pulsed Drain Current ²	-175	А
EAS	Single Pulse Avalanche Energy ³	31	mJ
P _D @T _C =25°C	Total Power Dissipation ⁴	31.2	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
Rejc	Thermal Resistance Junction-Case ¹	4	°C/W
R ₀ JA	Thermal Resistance Junction-Ambient ¹	61	°C/W

ElectricalCharacteristics(T J=25°C unless otherwise noted)

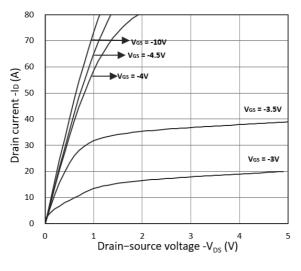
Parameter		Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Drain-Source Breakdown Voltage		V _{(BR)DSS}	$V_{GS} = 0V, I_D = -250\mu A$	-30	-	-	V	
Gate-body Leakage current		Igss	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA	
Zero Gate Voltage Drain	T _J =25°C	1	V _{DS} = -24V, V _{GS} = 0V	-	-	-1	μA	
Current	T _J =55°C	I _{DSS}	$V_{DS} = -24V$, $V_{GS} = 0V$	-	-	-5		
Gate-Threshold Voltage	Gate-Threshold Voltage		$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-1.0	-1.6	-2.5	V	
Drain-Source On-Resistance ²			V _{GS} = -10V, I _D = -12A	-	6	8.8	0	
		R _{DS(on)}	V _{GS} = -4.5V, I _D = -8A	D = -8A - 9		14	mΩ	
Forward Transconductance		g fs	V _{DS} = -5V, I _D = -20A	-	28	-	S	
Input Capacitance		C _{iss}		-	4320	-	pF	
Output Capacitance		Coss	$V_{DS} = -15V, V_{GS} = 0V, f = 1MHz$	-	529	-		
Reverse Transfer Capacitance		Crss		-	487	-		
Gate Resistance	Gate Resistance		V _{DS} = 0V, V _{GS} = 0V, f=1.0MHz	-	4.0	-	Ω	
Total Gate Charge		Qg		-	45	-	nC	
Gate-Source Charge		Q _{gs}	$V_{GS} = -10V, V_{DS} = -15V,$ $I_{D} = -15A$	-	8.5	-		
Gate-Drain Charge		Q _{gd}		-	12.8	-		
Turn-On Delay Time	Turn-On Delay Time			-	18.9	-	nS	
Rise Time		t _r	$V_{GS} = -10V, V_{DD} = -15V,$	-	15.7	-		
Turn-Off Delay Time		t _{d(off)}	$R_G = 2.5\Omega, I_D = -15A$	-	64.8	-		
Fall Time		t _f		-	36.5	-		
Diode Forward Voltage ²		V _{SD}	I _S = -1A, V _{GS} = 0V	-	-	-1	V	
Continuous Source Current ^{1,5}		Is	V _G =V _D =0V , Force Current	-	-	-70	Α	

Note:

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%
- 3. The EAS data shows Max. rating . The test condition is V_{DD} = -25V, V_{GS} = -10V, L= 0.1mH, I_{AS} = -25A
- 4.The power dissipation is limited by 150°C junction temperature
- 5. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



Typical Electrical And Thermal Characteristics (Curves)



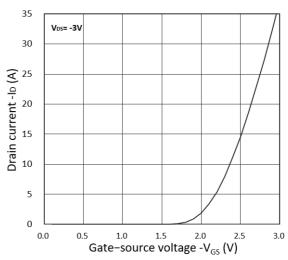


Figure 1. Output Characteristics

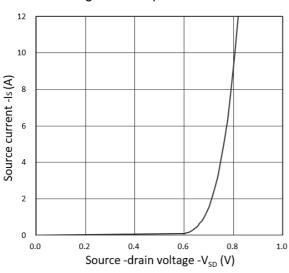


Figure 2. Transfer Characteristics

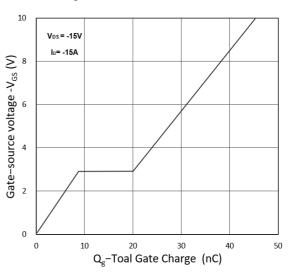


Figure 3. Forward Characteristics of Reverse

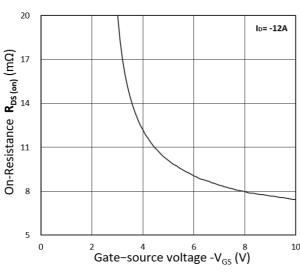


Figure 4. Gate Charge Characteristics

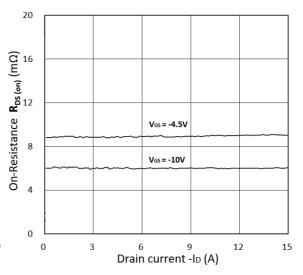


Figure 5. $R_{DS(on)}$ vs. V_{GS}

Figure 6. $R_{DS(on)}$ vs. I_D



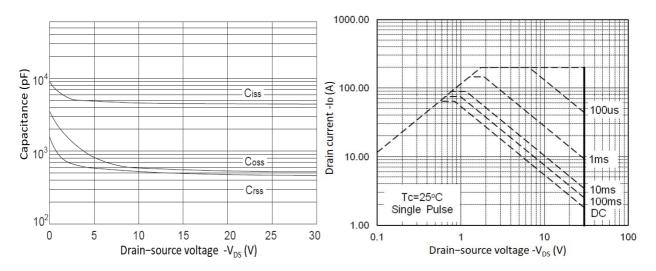


Figure 7. Capacitance Characteristics

Figure 8. Safe Operating Area

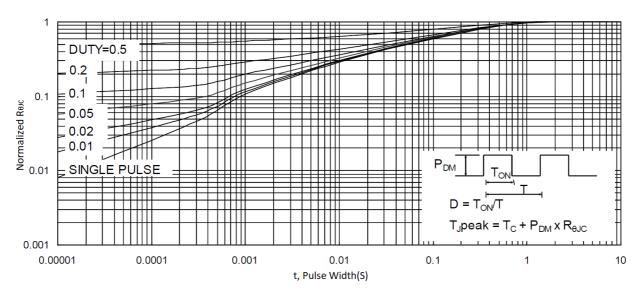


Figure 9. Normalized Maximum Transient Thermal Impedance

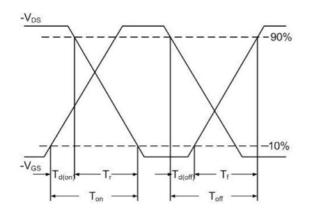


Figure 10. Switching Time Waveform

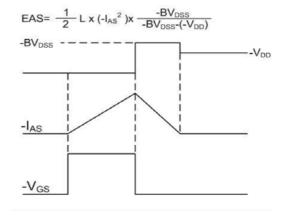


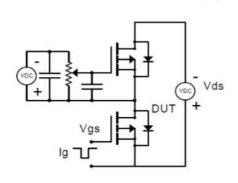
Figure 11. Unclamped Inductive Switching

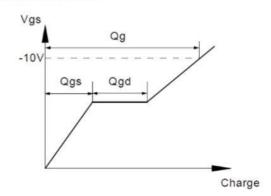
Waveform



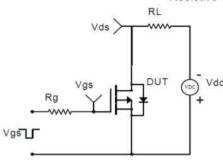
Test Circuit

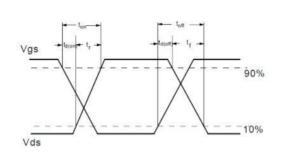
Gate Charge Test Circuit & Waveform



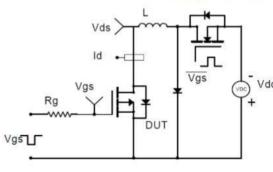


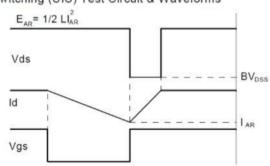
Resistive Switching Test Circuit & Waveforms



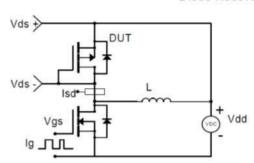


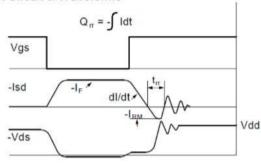
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





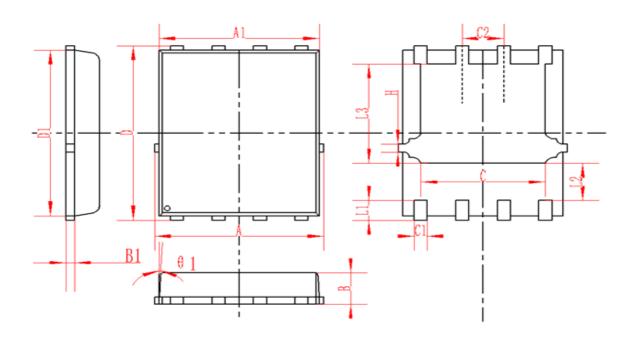
Diode Recovery Test Circuit & Waveforms







DFN3X3-8L(PowerPAK-SO-8) Package Information



SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX
А	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
В	0.9	0.95	1	0.035	0.037	0.039
B1	0.254REF		0.010REF			
С	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2		1.27TYP			0.5TYP	
θ1	8°	10°	12°	8°	10°	12°
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
Н	0.24	0.25	0.26	0.009	0.010	0.010



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